# **BUK7510-55AL**

# N-channel TrenchMOS standard level FET

Rev. 03 — 4 August 2009

**Product data sheet** 

## 1. Product profile

## 1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

#### 1.2 Features and benefits

- Q101 compliant
- Suitable for thermally demanding environments due to 175 ℃ rating
- Suitable for use in control systems due to stable operation in linear mode

### 1.3 Applications

- 12 V and 24 V loads
- Automotive systems

- DC motor control
- Repetitive clamped inductive switching

#### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25  \mathbb{C}; T_j \le 175  \mathbb{C}$		-	-	55	V
$I_D$	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ C};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	[1]	-	-	75	Α
P <sub>tot</sub>	total power dissipation	$T_{mb} = 25  \text{C}$ ; see Figure 2		-	-	300	W
Avalanch	ne ruggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 75 A; $V_{sup} \le$ 55 V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	-	1.1	J
Dynamic	characteristics						
$Q_{GD}$	gate-drain charge	$V_{GS}$ = 10 V; $I_D$ = 25 A; $V_{DS}$ = 44 V; $T_j$ = 25 °C; see Figure 15		-	50	-	nC
Static ch	aracteristics						
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ C}; \text{ see } \underline{\text{Figure 12}};$ $\text{see } \underline{\text{Figure 13}}$		-	8.5	10	mΩ

<sup>[1]</sup> Continuous current is limited by package.



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# **Pinning information**

Table 2. **Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain	mb	D
3	S	source		G (FX)
mb	D	mounting base; connected to drain	1 2 3	mbb076 S
			SOT78 (TO-220AB; SC-46)	

#### **Ordering information** 3.

Table 3. **Ordering information** 

**Product data sheet** 

Type number	Package		
	Name	Description	Version
BUK7510-55AL	TO-220AB; SC-46	Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78

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# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25  \text{C}; T_j \le 175  \text{C}$		-	55	V
$V_{DGR}$	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	55	V
$V_{GS}$	gate-source voltage			-20	20	V
I <sub>D</sub>	drain current	$T_{mb} = 25 \text{ C}$ ; $V_{GS} = 10 \text{ V}$ ; see <u>Figure 1</u> ; see <u>Figure 3</u>	[1][2]	-	122	Α
		$T_{mb} = 25 \text{ C}$ ; V <sub>GS</sub> = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	[3]	-	75	Α
		$T_{mb} = 100  \text{C}$ ; $V_{GS} = 10  \text{V}$ ; see Figure 1	[3]	-	75	Α
$I_{DM}$	peak drain current	$T_{mb}$ = 25 °C; $t_p \le 10 \mu s$ ; pulsed; see Figure 3		-	490	Α
P <sub>tot</sub>	total power dissipation	$T_{mb} = 25  \text{°C}$ ; see Figure 2		-	300	W
T <sub>stg</sub>	storage temperature			-55	175	${\mathbb C}$
Tj	junction temperature			-55	175	${\mathbb C}$
Source-dra	ain diode					
Is	source current	$T_{mb} = 25  $ C;	[1][2]	-	122	Α
		$T_{mb} = 25  $ C;	[3]	-	75	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}\!$		-	490	Α
Avalanche	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 75 A; $V_{sup}$ ≤ 55 V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	1.1	J
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy	see Figure 4	[4][5] [6]	-	-	J

<sup>[1]</sup> Current is limited by power dissipation chip rating.

<sup>[2]</sup> Refer to document 9397 750 12572 for further information.

<sup>[3]</sup> Continuous current is limited by package.

<sup>[4]</sup> Single-shot avalanche rating limited by maximum junction temperature of 175  $^{\circ}$ C.

<sup>[5]</sup> Repetitive avalanche rating limited by average junction temperature of 170 ℃.

<sup>[6]</sup> Refer to AN10273 for further information.

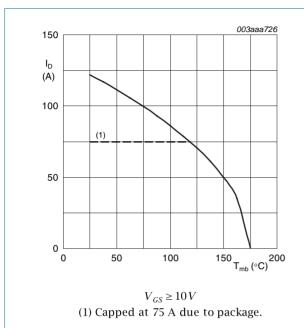


Fig 1. Continuous drain current as a function of mounting base temperature

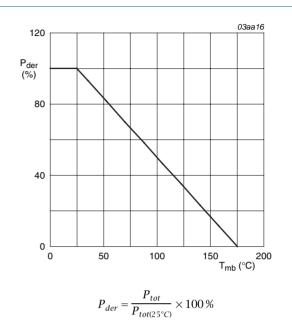
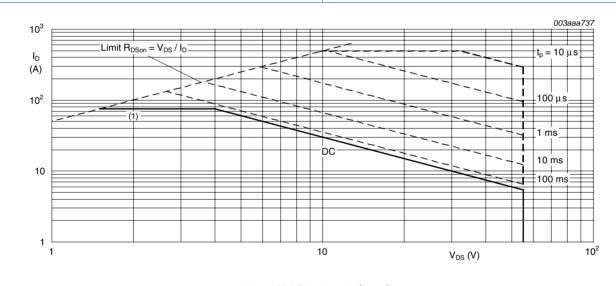
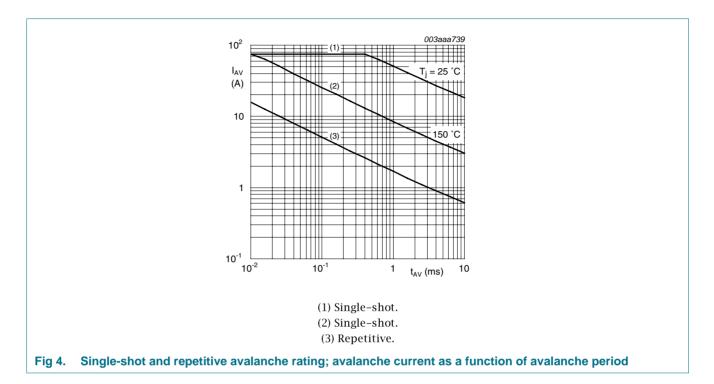


Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb}$  = 25 °C;  $I_{DM}$  is single pulse (1) Capped at 75 A due to package.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage



### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in still air	-	60	-	K/W
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 5	-	0.25	0.5	K/W

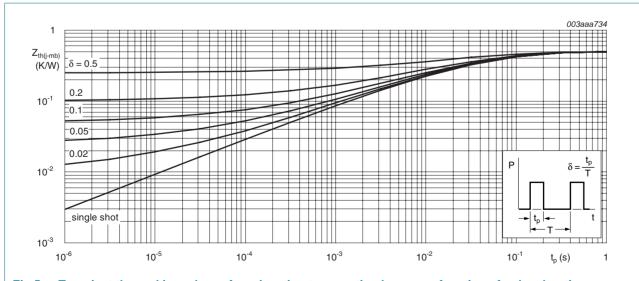


Fig 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

## 6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
-	aracteristics			- 7 12	A	J.iii
V <sub>(BR)DSS</sub>	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_i = -55 \degree$	50	-	_	V
breakdown voltage		$I_D = 250 \mu\text{A}, \text{V}_{GS} = 0 \text{V},  I_J = 55 \text{C}$ $I_D = 250 \mu\text{A}; \text{V}_{GS} = 0 \text{V};  T_i = 25 \text{C}$	55	<u>-</u>	_	V
$V_{GS(th)}$	gate-source threshold	$I_D = 250 \mu\text{A},  \text{V}_{GS} = 0.0,  \text{I}_{j} = 25.00;$ $I_D = 1 \text{mA};  \text{V}_{DS} = \text{V}_{GS};  \text{T}_{j} = 25.00;$	2	3	4	V
V GS(tn)	voltage	see Figure 10; see Figure 11				-
		$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = -55 ^{\circ}\text{C}$ ; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	-	4.4	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 175$ °C; see Figure 10; see Figure 11	1	-	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$	-	-	500	μΑ
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.05	10	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = +20 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
		$V_{DS} = 0 \text{ V; } V_{GS} = -20 \text{ V; } T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 175 \text{ C};$ see Figure 12; see Figure 13	-	-	20	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ C};$ see Figure 12; see Figure 13	-	8.5	10	mΩ
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge $I_D = 25 \text{ A}$ ; $V_{DS} = 44 \text{ V}$ ; $V_{GS} = 10 \text{ V}$ ;		-	124	-	nC
Q <sub>GS</sub>	gate-source charge	$T_j = 25  \text{°C}$ ; see Figure 15	-	22	-	nC
$Q_{GD}$	gate-drain charge		-	50	-	nC
V <sub>GS(pl)</sub>	gate-source plateau voltage	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; T_j = 25 \text{ C};$ see Figure 15	-	5	-	V
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	4710	6280	pF
C <sub>oss</sub>	output capacitance	$T_j = 25  \text{°C}$ ; see Figure 16	-	980	1180	pF
C <sub>rss</sub>	reverse transfer capacitance		-	560	770	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	33	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	117	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	132	-	ns
t <sub>f</sub>	fall time		-	95	-	ns
L <sub>D</sub>	internal drain inductance	from contact screw on package to centre of die; $T_i = 25 \ ^{\circ}\text{C}$	-	3.5	-	nΗ
		from drain lead 6mm from package to centre of die; $T_i = 25 ^{\circ}\text{C}$	-	4.5	-	Н
L <sub>S</sub>	internal source inductance	from source lead to source bond pad; T <sub>i</sub> = 25 ℃	-	7.5	-	nΗ
Source-d	rain diode	•				
V <sub>SD</sub>	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ C};$ see Figure 14	-	0.85	1.2	V
	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ;	-	73	-	ns
t <sub>rr</sub>						-

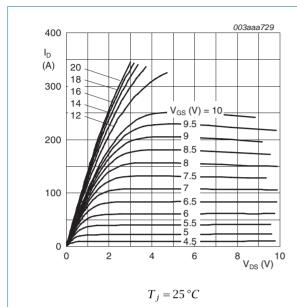


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

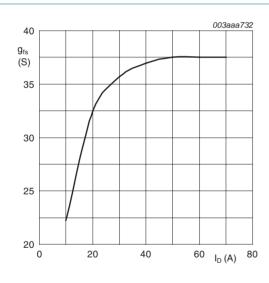


Fig 8. Forward transconductance as a function of drain current; typical values

 $T_i = 25 \,^{\circ}C; V_{DS} = 25 \,^{\circ}V$ 

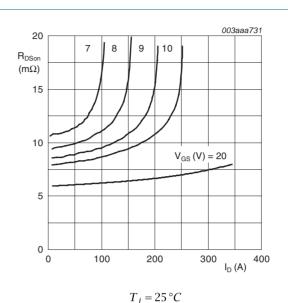


Fig 7. Drain-source on-state resistance as a function of drain current; typical values

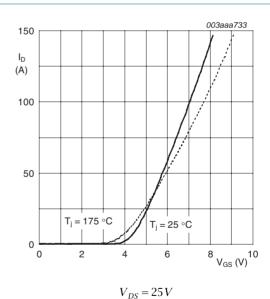
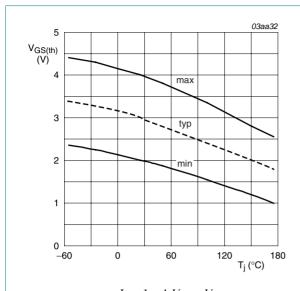
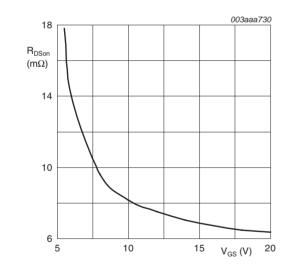


Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values

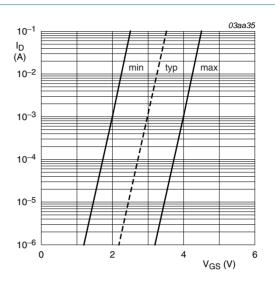


 $I_D = 1 \, mA; V_{DS} = V_{GS}$ 

Fig 10. Gate-source threshold voltage as a function of junction temperature

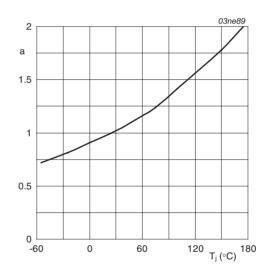


 $T_j=25\,^{\circ}C; I_D=25A$  Fig 12. Drain-source on-state resistance as a function of gate-source voltage; typical values



$$T_{j} = 25 \,^{\circ}C; V_{DS} = 5V$$

Fig 11. Sub-threshold drain current as a function of gate-source voltage



$$a = \frac{R_{DSon}}{R_{DSon}}$$

Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

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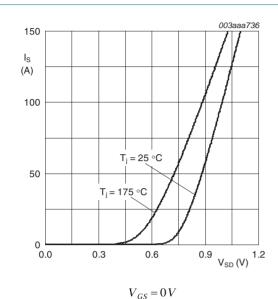
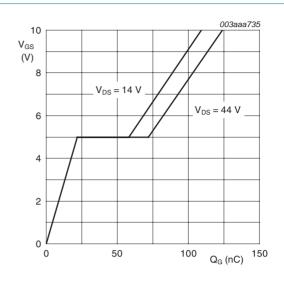
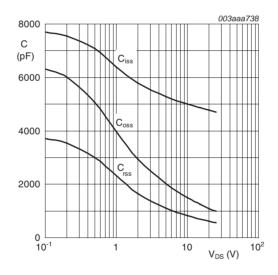


Fig 14. Source current as a function of source-drain voltage; typical values



$$T_i = 25 \,^{\circ}C; I_D = 25A$$

Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$ 

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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# Package outline

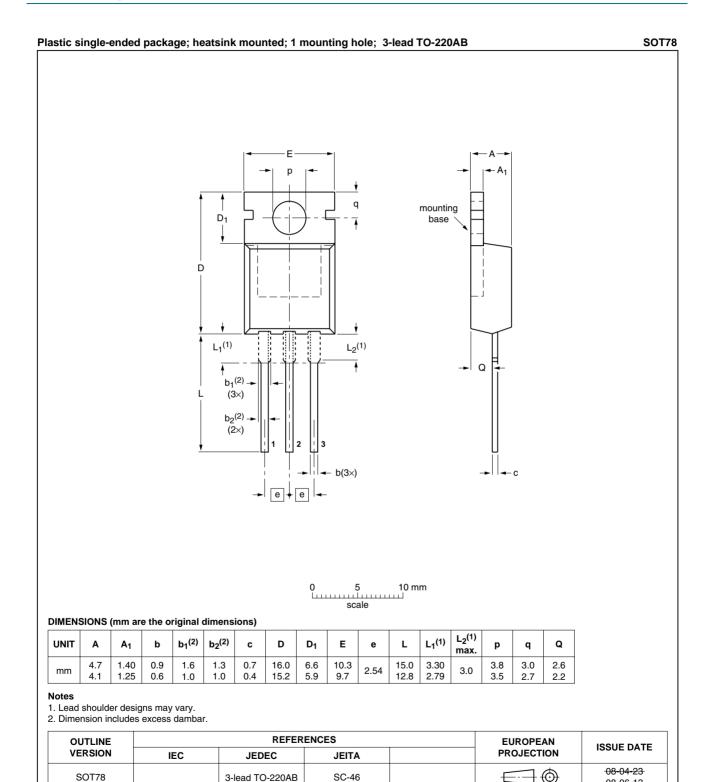


Fig 17. Package outline SOT78 (TO-220AB)

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#### N-channel TrenchMOS standard level FET

# 8. Revision history

#### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7510-55AL_3	20090804	Product data sheet	-	BUK7510-55AL_2
Modifications:	<ul> <li>Package or</li> </ul>	utline updated.		
BUK7510-55AL_2	20080103	Product data sheet	-	BUK75_7610_55AL_1
BUK75_7610_55AL_1	20050331	Product data sheet	-	-

#### N-channel TrenchMOS standard level FET

### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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